2. Interview Day residence (*i.e.*, as of

the day of the CCM interview). 3. Census Day address information for people who moved to the sample address since Census Day, and other addresses where a person might have been counted on Census Day.

4. Other information to help us determine where a person should have been counted as of Census Day (relative to our residence rules). For example, enumerators will probe for persons who might have been left off the household roster; ask additional questions about persons who moved from another address on Census Day to the sample address; collect additional information for persons with multiple addresses; and collect information on the addresses of other potential residences for household members.

5. Demographic information for each person in the household on Interview Day or Census Day, including name, date of birth, sex, race, ethnicity, and relationship.

As part of the CCM, we also will conduct a quality control operation—PI Reinterview. For this operation a sample of the CCM PI cases will be selected for a reinterview. This sample consists of approximately 500 housing units in Travis County, Texas; and 50 housing units on the Cheyenne River Reservation in South Dakota. The purpose of the reinterview is to determine if the source of the CCM PI data (e.g., a household member; a specific proxy respondent) can be confirmed. If not, then all cases completed by the original enumerator will be considered invalid, and reassigned for rework by a different enumerator.

The CCM PI and PI Reinterview operations will occur from July 3, 2006 to October 6, 2006. Data collected as a result of these interviews will be processed at our headquarters in Washington, DC.

Definition of Terms

Alternate Addresses—These are respondent provided addresses obtained during the CCM PI for other places where household members may have been counted on Census Day.

Components of Coverage Error—The two components of census coverage error are census omissions (missed persons) and erroneous inclusions. The latter includes duplicates, and persons who should not have been enumerated at a particular address (per our residence rules).

Net Coverage Error—Reflects the difference between omissions and erroneous inclusions. A positive net error indicates an undercount, while a negative net error indicates an overcount.

For more information about Census 2000 operations and coverage measurement efforts, please visit the following page of the Census Bureau's Web site: http://www.census.gov/dmd/www/refroom.html.

III. Data

OMB Number: 0607-xxxx.

Form Number: None.

Type of Review: Regular.

Affected Public: Individuals or Households.

Estimated Number of Respondents: 6,050.

Estimated Times Per Response: 20 Minutes.

Estimated Total Annual Burden Hours: 2,017.

Estimated Total Annual Cost to the Public: There is no cost to the respondents except their time to respond.

Respondent Obligation: Mandatory. *Legal Authority:* Title 13 of the United States Code, Sections 141 and 193.

IV. Request for Comments

Comments are invited on: (a) Whether the proposed collection of information is necessary for the proper performance of the functions of the agency, including whether the information shall have practical utility: (b) the accuracy of the agency's estimate of the burden (including hours and cost) of the proposed collection; (c) ways to enhance the quality, utility, and clarity of the information to be collected; and (d) ways to minimize the burden of the collection of information on respondents, including through the use of automated collection techniques or other forms of information technology.

Comments submitted in response to this notice will be summarized and/or included in the request for OMB approval of the information collection; they also will become a matter of public record.

Dated: June 16, 2005.

Madeleine Clayton,

Management Analyst, Office of the Chief Information Officer. [FR Doc. 05–12260 Filed 6–21–05; 8:45 am]

BILLING CODE 3510-07-P

U.S. DEPARTMENT OF COMMERCE

Foreign Trade Zones Board

Order No. 1398

Approval for Subzone Expansion and Permanent Manufacturing Authority, (Polyethylene Tubing), Foreign Trade Subzone 119B, Wirsbo Company, Apple Valley, Minnesota

Pursuant to its authority under the Foreign–Trade Zones Act of June 18, 1934, as amended (19 U.S.C. 81a–81u), the Foreign– Trade Zones Board (the Board) adopts the following Order:

Whereas, the Greater Metropolitan Area Foreign Trade Zone Commission, grantee of FTZ 119 (Minneapolis, Minnesota), has requested authority on behalf of the Wirsbo Company (Wirsbo), operator of FTZ 119B, at the Wirsbo polyethylene (HDPE) tubing manufacturing plant in Apple Valley, Minnesota, to expand Subzone 119B to include a new site in Burnsville, Minnesota, and to extend authority to manufacture polyethylene tubing under FTZ procedures on a permanent basis (FTZ Doc. 63–2003, filed 12/12/2003);

Whereas, notice inviting public comment was given in the **Federal Register** (68 FR 71060, 12–22–2003);

Whereas, the Board adopts the findings and recommendations of the examiner's report, and finds that the requirements of the FTZ Act and the Board's regulations are satisfied, and that approval of the application is in the public interest;

Now, therefore, the Board hereby approves the request, subject to the FTZ Act and the Board's regulations, including Section 400.28.

Signed at Washington, DC, this 9th day of June, 2005.

Joseph A. Spetrini,

Acting Assistant Secretary of Commerce for Import Administration, Alternate Chairman, Foreign–Trade Zones Board. Attest:

Dennis Puccinelli,

Executive Secretary. [FR Doc. 05–12370 Filed 6–21–05; 8:45 am] BILLING CODE 3510–DS–S

U.S. DEPARTMENT OF COMMERCE

Foreign–Trade Zones Board

Order No. 1396

Expansion of Foreign–Trade Zone 141, Monroe County, New York, Area

Pursuant to its authority under the Foreign–Trade Zones Act of June 18, 1934, as amended (19 U.S.C. 81a–81u), the Foreign– Trade Zones Board adopts the following Order: *Whereas*, the County of Monroe, New York, grantee of Foreign–Trade Zone 141, submitted an application to the Board for authority to expand FTZ 141 to include a site (Site 11- 314 acres) at Rochester Technology Park, 789 Elmgrove Road, Rochester (Monroe County), New York, and to remove this area from Site 4 of FTZ 141A (Kodak), within the Rochester Customs port of entry (FTZ Docket 52–2004; filed 11/17/ 04);

Whereas, notice inviting public comment was given in the **Federal Register** (69 FR 68127, 11/23/04), and the application has been processed pursuant to the FTZ Act and the Board's regulations; and,

Whereas, the Board adopts the findings and recommendations of the examiner's report, and finds that the requirements of the FTZ Act and Board's regulations are satisfied, and that the proposal is in the public interest;

Now, therefore, the Board hereby orders:

The application to expand FTZ 141 is approved, subject to the Act and the Board's regulations, including Section 400.28.

Signed at Washington, DC, this 9th day of June, 2005.

Joseph A. Spetrini,

Acting Assistant Secretary of Commerce for Import Administration, Alternate Chairman, Foreign–Trade Zones Board Attest:

Dennis Puccinelli,

Executive Secretary.

[FR Doc. 05–12368 Filed 6–21–05; 8:45 am] BILLING CODE 3510–DS–S

DEPARTMENT OF COMMERCE

Foreign–Trade Zones Board

Order No. 1397

Expansion of Foreign–Trade Zone 163, Ponce, Puerto Rico, Area

Pursuant to its authority under the Foreign–Trade Zones Act of June 18, 1934, as amended (19 U.S.C. 81a–81u), the Foreign– Trade Zones Board (the Board) adopts the following Order:

Whereas, Codezol, C.D., the grantee of Foreign–Trade Zone 163, submitted an application to the Board for authority to remove the time restriction on Site 4 (Guayama) and to add two new sites (342 acres) at Merecedita Industrial Park (Site 5), and Coto Laurel Industrial Park (Site 6), in the Ponce, Puerto Rico, area, adjacent to the Ponce Customs port of entry (FTZ Docket 39–2004; filed 8/25/ 04); *Whereas*, notice inviting public comment was given in the **Federal Register** (69 FR 53886, 9/3/04), and the application has been processed pursuant to the FTZ Act and the Board's regulations; and,

Whereas, the Board adopts the findings and recommendations of the examiner's report, and finds that the requirements of the FTZ Act and Board's regulations are satisfied, and that the proposal is in the public interest;

Now, therefore, the Board hereby orders:

The application to expand FTZ 163 and to remove the time restriction on Site 4 is approved, subject to the Act and the Board's regulations, including Section 400.28.

Signed at Washington, DC, this 9th day of June, 2005.

Joseph A. Spetrini,

Acting Assistant Secretary of Commerce, for Import Administration, Alternate Chairman, Foreign–Trade Zones Board Attest:

Attest:

Dennis Puccinelli,

Executive Secretary. [FR Doc. 05–12369 Filed 6–21–05; 8:45 am] BILLING CODE 3510–DS–S

DEPARTMENT OF COMMERCE

International Trade Administration

Applications for Duty–Free Entry of Scientific Instruments

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89–651; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be filed within 20 days with the Statutory Import Programs Staff, U.S. Department of Commerce, Washington, D.C. 20230. Applications may be examined between 8:30 A.M. and 5:00 P.M. in Suite 4100W, U.S. Department of Commerce, Franklin Court Building, 1099 14th Street, NW, Washington, D.C.

Docket Number: 05–018. Applicant: Oregon Health and Science University, Neurological Sciences Institute, 5050 N.W. 185th Avenue, Beaverton, OR 97006. Instrument: TriMScope Beam Multiplexor System. Manufacturer: La Vision BioTech GmbH, Germany. Intended Use: The instrument is intended to be used to study the anatomy and physiology of the animal brain at the subcellular level and the optical correlates of its electrical activity in order to resolve the fine structural alterations after global brain ischemia, prior to neuronal death, to identify early timepoints in which therapies can be delivered to prevent brain death. It will employ multiple infrared light beams prior to their passage through a microscope to illuminate the subsurface of the brain at a discrete focal plane. Application accepted by Commissioner of Customs: May 23, 2005.

Docket Number: 05–020. Applicant: University of California, San Diego, 9500 Gilman Drive, La Jolla, CA 92093– 0332. Instrument: Electron Microscope, Model Technai G² Sphera Manufacturer: FEI Company, The Netherlands. Intended Use: The instrument is intended to be used to image and study, among other things:

1. The structure and the mechanisms of action of various viruses.

2. Cell motility and adhesion of ventral membrane preparations of fibroblast cells.

3. The function of MsbA in membrane transport with drug-resistant bacteria.

4. Intercellular communication involving connexin protein and its function in x–linked diseases.

5. Trans–membrane signaling within human platelet protein integrin.

These studies will use low–dose cryoelectron microscopy techniques. Application accepted by Commissioner of Customs: June 8, 2005.

Docket Number: 05–021. Applicant: University of California, San Diego, 9500 Gilman Drive, La Jolla, CA 92093– 0332. Instrument: Electron Microscope, Model Technai G² Polara. Manufacturer: FEI Company, The Netherlands. Intended Use: The instrument is intended to be used to image and study, among other things:

1. The structure and the mechanisms of action of various viruses.

2. Cell motility and adhesion of ventral membrane preparations of fibroblast cells.

3. The function of MsbA in membrane transport with drug-resistant bacteria.

4. Intercellular communication involving connexin protein and its function in x–linked diseases.

5. Trans–membrane signaling within human platelet protein integrin.

These studies will use low–dose cryoelectron microscopy techniques.